

#### 3108A-VB TO252 Datasheet

## N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$ Max.	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)			
	0.0050 at V <sub>GS</sub> = 10 V	75 <sup>a</sup>				
80	0.0070 at V <sub>GS</sub> = 6.0 V	65 <sup>a</sup>	17.1 nC			
	$0.0087$ at $V_{GS} = 5.0 \text{ V}$	54				

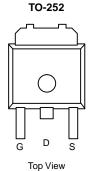
#### **FEATURES**

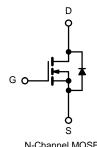
- Trench Power MOSFET
- 100 % R<sub>a</sub> and UIS Tested



#### **APPLICATIONS**

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting





N-Channel MOSFET

Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	80	V	
Gate-Source Voltage	V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		75 <sup>a</sup>	
Continuous Dunis Comment /T 150 °C)	T <sub>C</sub> = 70 °C		62.7	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	28.6 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		24.9 <sup>b, c</sup>	
Pulsed Drain Current (t = 100 μs)		I <sub>DM</sub>	150	Α
Continuous Courses Ducin Diado Coursest	T <sub>C</sub> = 25 °C		75a	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	4.5 <sup>b, c</sup>	
Single Pulse Avalanche Current	. 0.1	I <sub>AS</sub>	30	
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	45	mJ
	T <sub>C</sub> = 25 °C		62.5	
Manianum Danier Disaination	T <sub>C</sub> = 70 °C		40	10/
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 <sup>b, c</sup>	W
	T <sub>A</sub> = 70 °C		3.2 <sup>b, c</sup>	
Operating Junction and Storage Temperature R	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150		
Soldering Recommendations (Peak Temperature		260	- °C	

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	R <sub>thJA</sub>	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	1.5	2.0	C/VV	

#### **Notes**

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- d. The TO-220 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70  $^{\circ}\text{C/W}.$



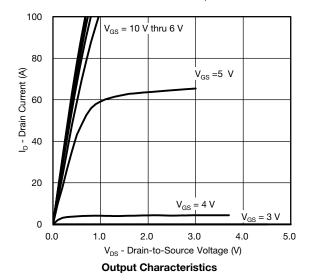
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V <sub>DS</sub> Temperature Coefficient	emperature Coefficient ΔV <sub>DS</sub> /T <sub>L</sub>			37		m\//°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th</sub> )	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
	_ (0,	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0050		1	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 6 \text{ V}, I_D = 15 \text{ A}$		0.0070		Ω	
	, ,	$V_{GS} = 5.0 \text{ V}, I_D = 10 \text{ A}$		0.0087			
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S	
Dynamic <sup>b</sup>							
Input Capacitance C <sub>iss</sub>			1855				
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		950		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			76		1	
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5	54		
Total Gate Charge	Qg	$V_{DS} = 40 \text{ V}, V_{GS} = 6 \text{ V}, I_D = 10 \text{ A}$		22	33	nC	
				17.1	26		
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	$Q_{gd}$			7.3			
Output Charge	Q <sub>oss</sub>	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$		57	86		
Gate Resistance	$R_g$	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			12	24		
Rise Time	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		8	16		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10^{\circ} \text{A}, V_{GEN} = 10^{\circ} \text{V}, R_g = 1^{\circ} \Omega$		32	64		
Fall Time	t <sub>f</sub>			7	14		
Turn-On Delay Time	t <sub>d(on)</sub>			14	28	ns	
Rise Time	t <sub>r</sub>			11	22	1	
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60		
Fall Time	t <sub>f</sub>			8	16		
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			75	۸	
Pulse Diode Forward Current (t = 100 μs)	I <sub>SM</sub>				150	A	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			38	75	ns	
Body Diode Reverse Recovery Charge	de Reverse Recovery Charge			36	70	nC	
Reverse Recovery Fall Time	ta	IF = 10 A. dl/dt = 100 A/us. 1 i = 25 °C		19		ns	
Reverse Recovery Rise Time	t <sub>b</sub>			19			

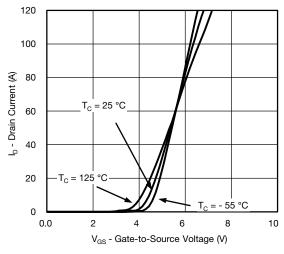
#### Notes

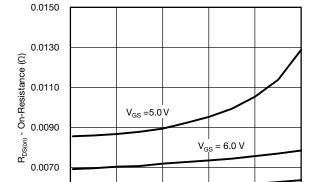
- a. Pulse test; pulse width  $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

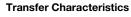
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

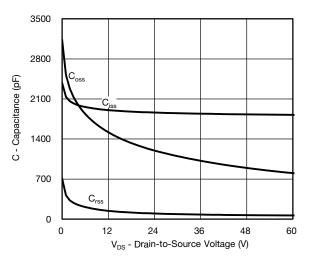












# I<sub>D</sub> - Drain Current (A) On-Resistance vs. Drain Current

60

40

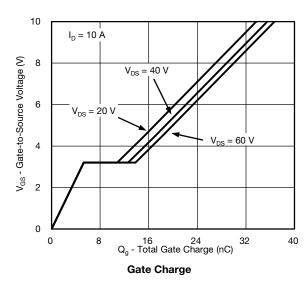
0.0050

0

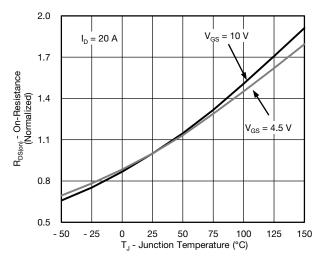
 $V_{GS} = 10 \text{ V}$ 

100

80

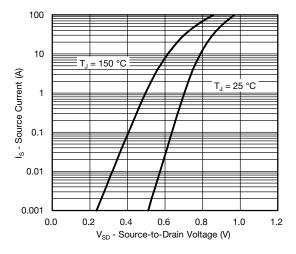


Capacitance

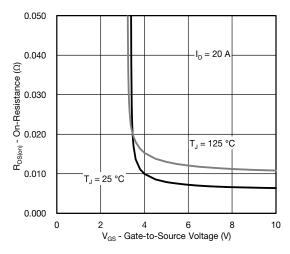


On-Resistance vs. Junction Temperature

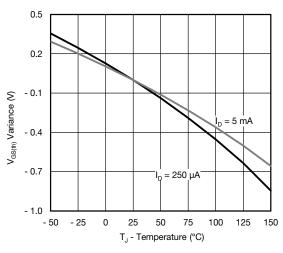




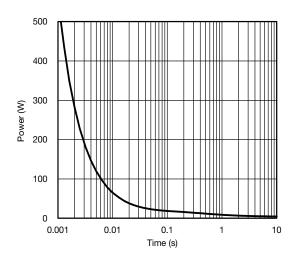
Source-Drain Diode Forward Voltage



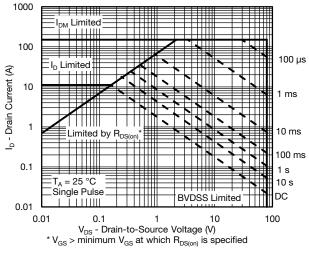
On-Resistance vs. Gate-to-Source Voltage



**Threshold Voltage** 

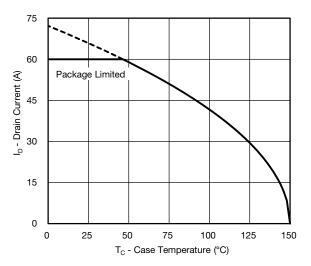


Single Pulse Power, Junction-to-Ambient

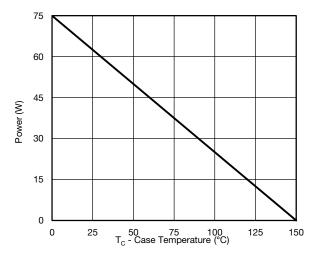


Safe Operating Area, Junction-to-Ambient

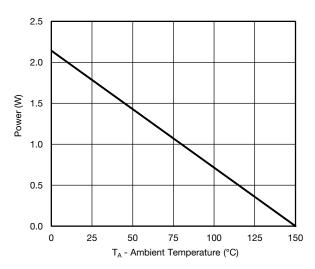




#### **Current Derating\***



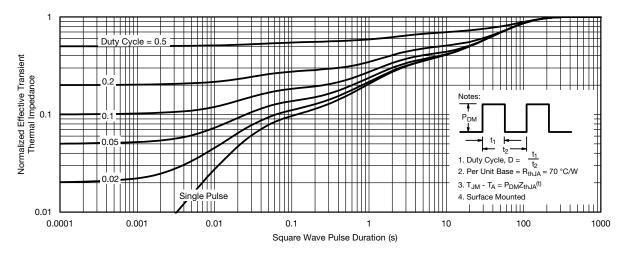




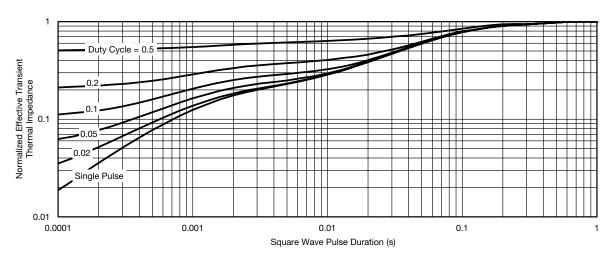
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





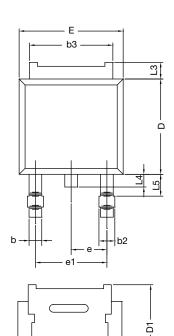
Normalized Thermal Transient Impedance, Junction-to-Ambient



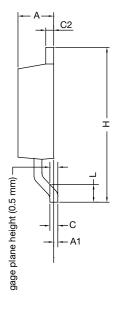
Normalized Thermal Transient Impedance, Junction-to-Case



### **TO-252AA CASE OUTLINE**



E1



	MILLIMETERS INCHES			HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	2.28 BSC		BSC	
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-	0247-Rev. M,	24-Dec-12			

ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347

#### Note

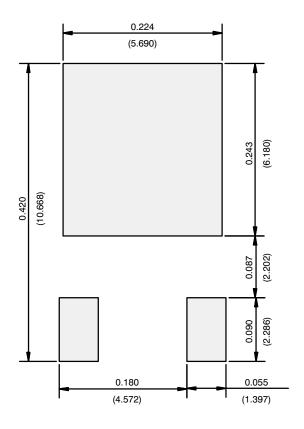
• Dimension L3 is for reference only.

服务热线:400-655-8788

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#### **RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)**



Recommended Minimum Pads Dimensions in Inches/(mm)



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